		04/05	2003/	USPAT; US-PGPUB	705/416.ccls.	37	BRS	47
		04/05	2003/04/05 20:07	IPO; IT;	(barcode dataform symbology ((bar optical readable) adj1 (code label indicia symbol))) near5 (scan\$4 read\$3 terminal pos (point adj1 sale) checkout (check adj out)) near5 (scale weigh\$3) near5 (keypad keyboard input\$3)	11	BRS	46
		04/05	2003/04/20:03	USPAT; US-PGPUB		3 5	BRS	45 5
		04/05	2003/04/05	USPAT; US-PGPUB	(6456981.pn. 5950173.pn. 5754655.pn. 6502749.pn. 6539422.pn. 20010020641.pn. 5256863.pn. 5886336.pn. 5924079.pn. 6237852.pn. 6241149.pn.) and (ethernet nic (network adjl card))	2	BRS	44
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